

INFORMATION DISCLOSED CITATION <i>(Use several sheets if necessary)</i>			Docket Number (Optional)	Application Number
			Applicant(s) Larry Hryshko	
			Filing Date 10530868 - GAU	Group Art Unit 1657

U.S. PATENT DOCUMENTS

*EXAMINER INITIAL	REF	DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE

U.S. PATENT APPLICATION PUBLICATIONS

*EXAMINER INITIAL	REF	DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
/A.W./		2002/064841	May 30/02	Mark A Reed et al.			

FOREIGN PATENT DOCUMENTS

	REF	DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	Translation	
							YES	NO
/A.W./		02/29402	Apr. 11/02	WO				
/A.W./		01/94939	Dec. 13/01	WO				
/A.W./		01/48475	July 5/01	WO				
/A.W./		02/64253	Aug 22/02	WO				

OTHER DOCUMENTS *(Including Author, Title, Date, Pertinent Pages, Etc.)*

/A.W./		Mosbacher J et al, "Studying Membranes With Scanning Force Microscopy and Patch-Clamp Technique", Journal of Vacuum Science and Technology: Part B, American Institute of Physics, vol. 14, no. 2, March 1, 1996, pages 1449-1452.

EXAMINER	/Amanda Wood/	DATE CONSIDERED	9/2008
----------	---------------	-----------------	--------

EXAMINER: Initial if citation considered, whether or not citation is in conformance with MPEP Section 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.